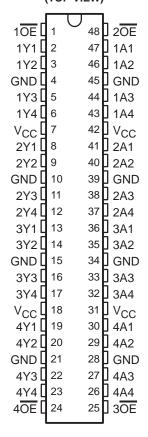
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- Members of the Texas Instruments
 Widebus™ Family
- State-of-the-Art EPIC-IIB™ BiCMOS Design Significantly Reduces Power Dissipation
- Latch-Up Performance Exceeds 500 mA Per JEDEC Standard JESD-17
- Typical V_{OLP} (Output Ground Bounce)
 1 V at V_{CC} = 5 V, T_A = 25°C
- Distributed V_{CC} and GND Pin Configuration Minimizes High-Speed Switching Noise
- Flow-Through Architecture Optimizes PCB Layout
- High-Drive Outputs (–32-mA I_{OH}, 64-mA I_{OI})
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages and 380-mil Fine-Pitch Ceramic Flat (WD) Package Using 25-mil Center-to-Center Spacings

description

The SN54ABT16244 and SN74ABT16244A are 16-bit buffers and line drivers designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. These devices can be used as four 4-bit buffers, two 8-bit buffers, or one 16-bit buffer. These devices provide true outputs and symmetrical \overline{OE} (active-low output-enable) inputs.

SN54ABT16244 . . . WD PACKAGE SN74ABT16244A . . . DGG, DGV, OR DL PACKAGE (TOP VIEW)



To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54ABT16244 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ABT16244A is characterized for operation from –40°C to 85°C.

FUNCTION TABLE (each buffer)

	`	
INP	UTS	OUTPUT
OE	Α	Υ
L	Н	Н
L	L	L
Н	X	Z



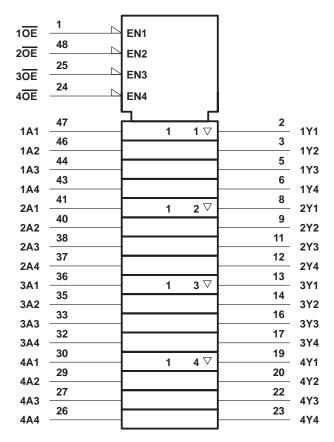
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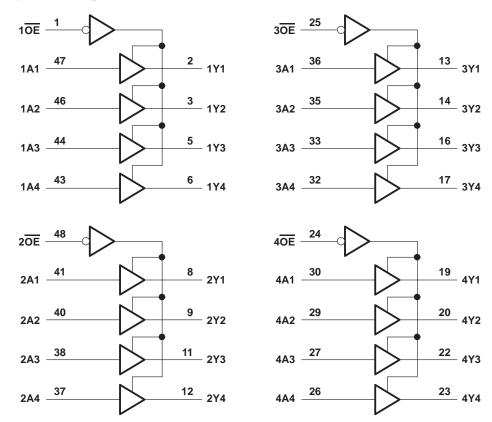
logic symbol†



 $[\]ensuremath{^{\dagger}}$ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Input voltage range, V _I (see Note 1)	
	ver-off state, V _O 0.5 V to 5.5 V
	16244 96 mA
SN74AB1	T16244A 128 mA
Input clamp current, I _{IK} (V _I < 0)	–18 mA
Output clamp current, I _{OK} (V _O < 0)	–50 mA
Package thermal impedance, θ_{JA} (see Note 2): DGG	package 89°C/W
DGV	package 93°C/W
DL pa	ackage 94°C/W
Storage temperature range, T _{stg}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51.



SN54ABT16244, SN74ABT16244A 16-BIT BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

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recommended operating conditions (see Note 3)

		SN54AB1	Г16244	SN74ABT1	UNIT		
			MIN	MAX	MIN	MAX	UNIT
V _{CC} Supply voltage		4.5	5.5	4.5	5.5	V	
VIH High-level input voltage		2		2		V	
V _{IL} Low-level input voltage			0.8		0.8	V	
V _I Input voltage		0	VCC	0	VCC	V	
IOH High-level output current			-24		-32	mA	
I _{OL} Low-level output current			48		64	mA	
Δt/Δν	Input transition rise or fall rate	Outputs enabled		10		10	ns/V
T _A Operating free-air temperature		-55	125	-40	85	°C	

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAA	AETED	TEST CO	NDITIONS	T,	_A = 25°C	†	SN54AB1	Г16244	SN74ABT1	UNIT		
PARAM	MEIER	lesi co	NDITIONS	MIN	TYP [‡]	MAX	MIN	MAX	MIN	MAX	UNII	
VIK		$V_{CC} = 4.5 \text{ V},$	I _I = -18 mA			-1.2		-1.2		-1.2	V	
		$V_{CC} = 4.5 \text{ V},$	$I_{OH} = -3 \text{ mA}$	2.5			2.5		2.5			
V		V _{CC} = 5 V,	$I_{OH} = -3 \text{ mA}$	3			3		3		V	
VOH		$V_{CC} = 4.5 \text{ V}$ $I_{OH} = -24 \text{ mA}$ 2 2					V					
		VCC = 4.5 V	$I_{OH} = -32 \text{ mA}$	2*					2			
VOL		V _{CC} = 4.5 V	I _{OL} = 48 mA			0.55		0.55			V	
VOL		VCC = 4.5 V	$I_{OL} = 64 \text{ mA}$			0.55*				0.55	V	
V _{hys}					100						mV	
II		$V_{CC} = 5.5 \text{ V},$	$V_I = V_{CC}$ or GND			±1		±1		±1	μΑ	
lozh		$V_{CC} = 5.5 \text{ V},$	V _O = 2.7 V			10§		10		10§	μΑ	
lozL		V _{CC} = 5.5 V,	V _O = 0.5 V			-10§		-10		-10§	μΑ	
l _{off}		$V_{CC} = 0$,	V_I or $V_O \le 4.5 \text{ V}$			±100				±100	μΑ	
ICEX		V _C C = 5.5 V, V _O = 5.5 V	Outputs high			50		50		50	μА	
IOI		$V_{CC} = 5.5 \text{ V},$	V _O = 2.5 V	-50	-100	-180	-50	-180	-50	-180	mA	
		V _{CC} = 5.5 V,	Outputs high			3		2		3		
Icc		$I_{O} = 0$,	Outputs low			32		32		32	mA	
		$V_I = V_{CC}$ or GND	Outputs disabled			3		2		3		
	Data	V _{CC} = 5.5 V, One input at 3.4 V,	Outputs enabled			0.05		1.5		0.05		
∆lcc#	inputs	Other inputs at VCC or GND	Outputs disabled			0.05		1		0.05	mA	
	Control inputs	$V_{CC} = 5.5 \text{ V}$, One inp Other inputs at V_{CC}				0.05		1.5		0.05		
Ci		V _I = 2.5 V or 0.5 V			3						pF	
Co		V _O = 2.5 V or 0.5 V			8						pF	

^{*} On products compliant to MIL-PRF-38535, this parameter does not apply.

[#]This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.



[†] Characteristics for $T_A = 25$ °C apply to the SN74ABT16244A only.

[‡] All typical values are at $V_{CC} = 5 \text{ V}$.

[§] This data sheet limit may vary among suppliers.

[¶] Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

SN54ABT16244, SN74ABT16244A 16-BIT BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

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switching characteristics over recommended ranges of supply voltage and operating free-air temperature, C_L = 50 pF (unless otherwise noted) (see Figure 1)

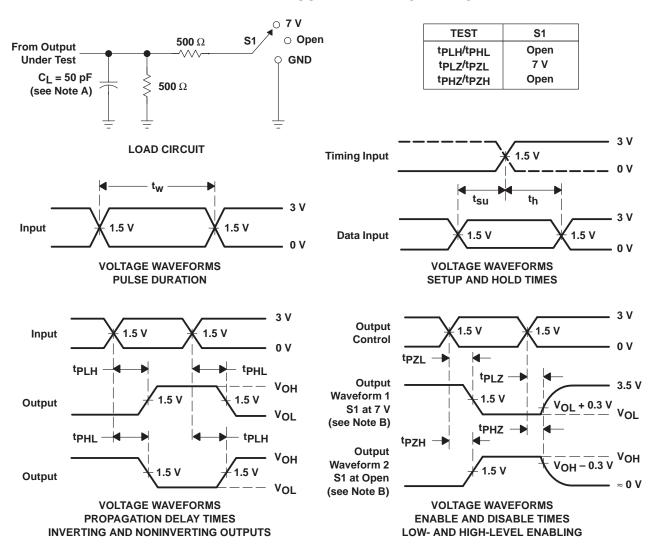
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V ₍	CC = 5 V A = 25°C	', ;	MIN	MAX	UNIT
			MIN	TYP	MAX			
t _{PLH}	А	V	0.7	2.3	3.2	0.7	3.6	ne
^t PHL		ı	0.5	2.6	3.7	0.5	4.2	ns
^t PZH	ŌĒ	V	0.7	3	4	0.7	4.9	ns
^t PZL		ı	0.9	3.2	5.5	0.9	6.5	115
^t PHZ	ŌĒ	V	1.7	3.6	5	1.7	6	nc
t _{PLZ}		ı	1.5	2.9	4.7	1.5	5.7	ns

switching characteristics over recommended ranges of supply voltage and operating free-air temperature, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V ₍	CC = 5 V 4 = 25°C	/, ;	MIN	MAX	UNIT
			MIN	TYP	MAX			
tpLH	А	A V	1	2.3	3.2	1	3.5	ne
t _{PHL}			'	1	2.6	3.7	1	4.1
^t PZH	ŌĒ		1	3	3.8	1	4.8	ns
tPZL		'	1	3.2	4	1	4.8	115
^t PHZ	ŌĒ		1	3.6	4.4	1	4.8	ns
t _{PLZ}		1	1	2.9	3.7	1	4.1	115

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PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_{\Omega} = 50 \Omega$, $t_r \leq 2.5$ ns. $t_f \leq 2.5$ ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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